Notice of References Cited Application/Control No. 10/789,744 Examiner LEONARD S. LIANG Applicant(s)/Patent Under Reexamination HO, WAI YUEN Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | Α | US-1,935,589 | 11-1933 | DODGE ADIEL Y | 475/255 |
| * | В | US-6,770,005 | 08-2004 | Aikawa et al. | 475/5 |
| * | C | US-4,674,612 | 06-1987 | Ogura, Masami | 192/48.92 |
| * | D | US-3,884,097 | 05-1975 | Avramidis et al. | 475/208 |
| * | Е | US-4,827,799 | 05-1989 | Jang, Lian-Sheng | 475/258 |
| * | F | US-2,891,421 | 06-1959 | GRATTAN WORTHIN F | 475/258 |
| | G | US- | | | |
| | Ι | US- | | | |
| | - | US- | | | |
| | J | US- | | | |
| | К | US- | | | |
| | L | US- | | | |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|--------------|----------------|
| | N | JP 2000104799 A | 04-2000 | Japan | OKADA et al. | |
| | 0 | | | | | |
| | Р | | | | | |
| | Ø | | | | | |
| | R | | | | | |
| | S | | | | | |
| | Т | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | ٧ | |
| | W | |
| | × | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.